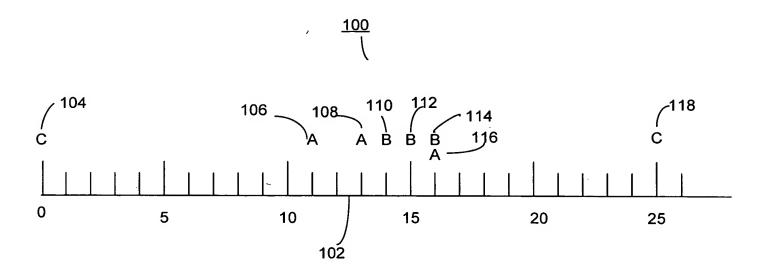
TITLE: SYSTEM/METHOD FOR ANALYZING A PATTERN IN A TIME-STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707 MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229

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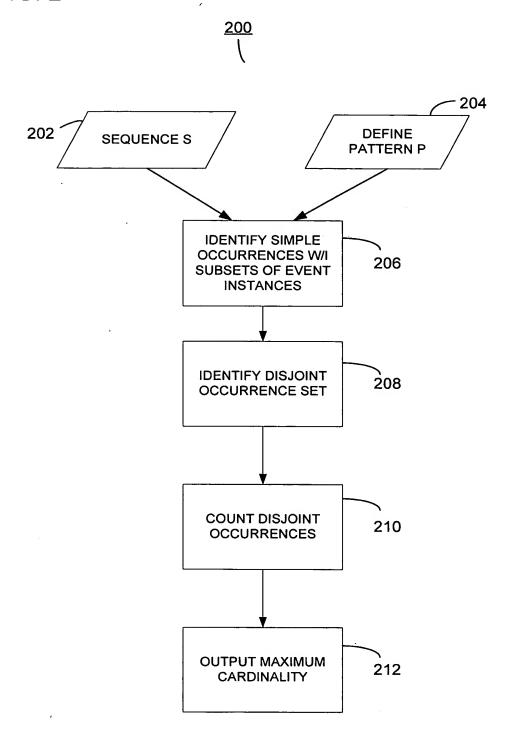
FIG. 1



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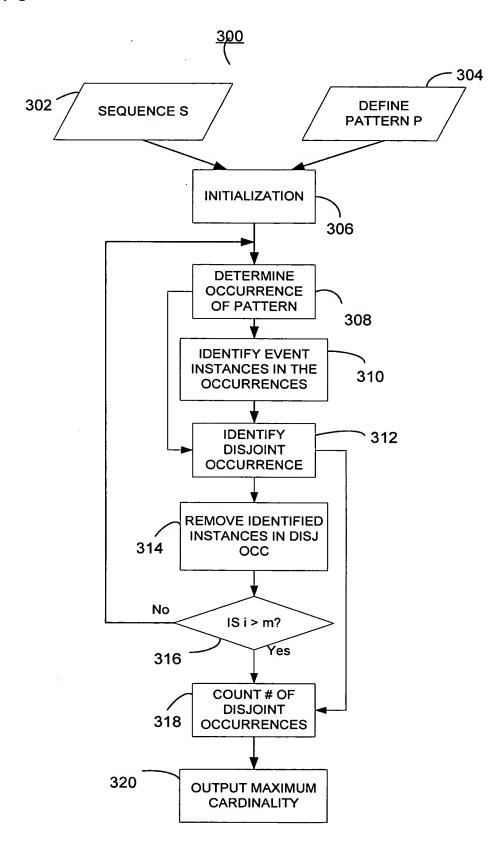
FIG. 2



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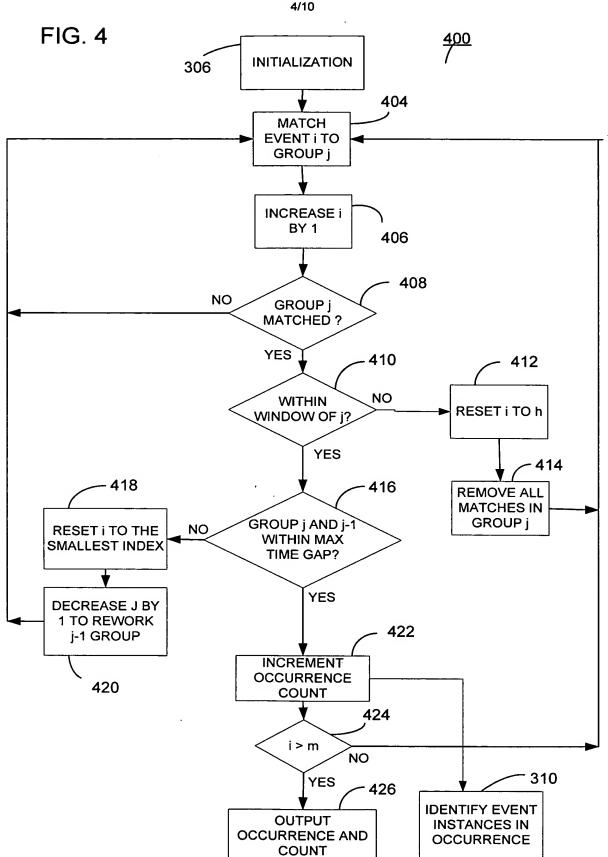
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FIG. 3



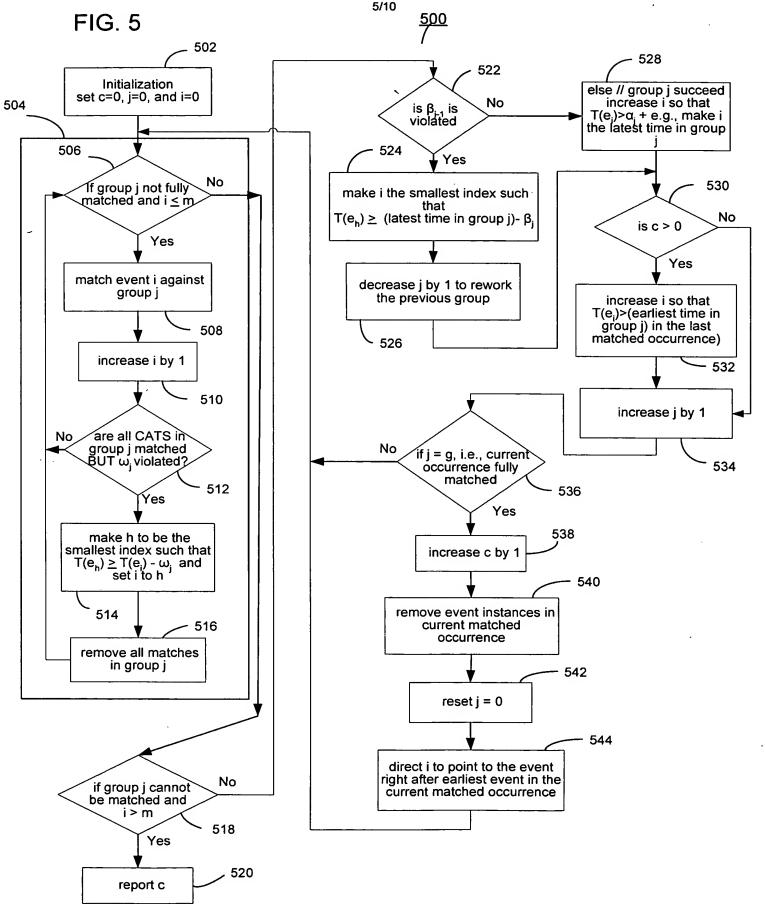
STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707

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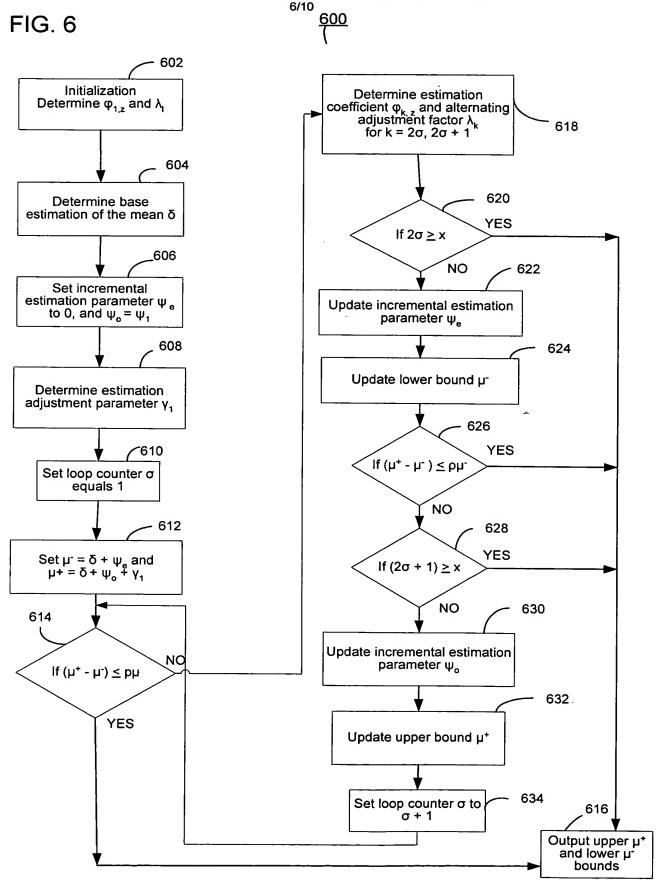
STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707

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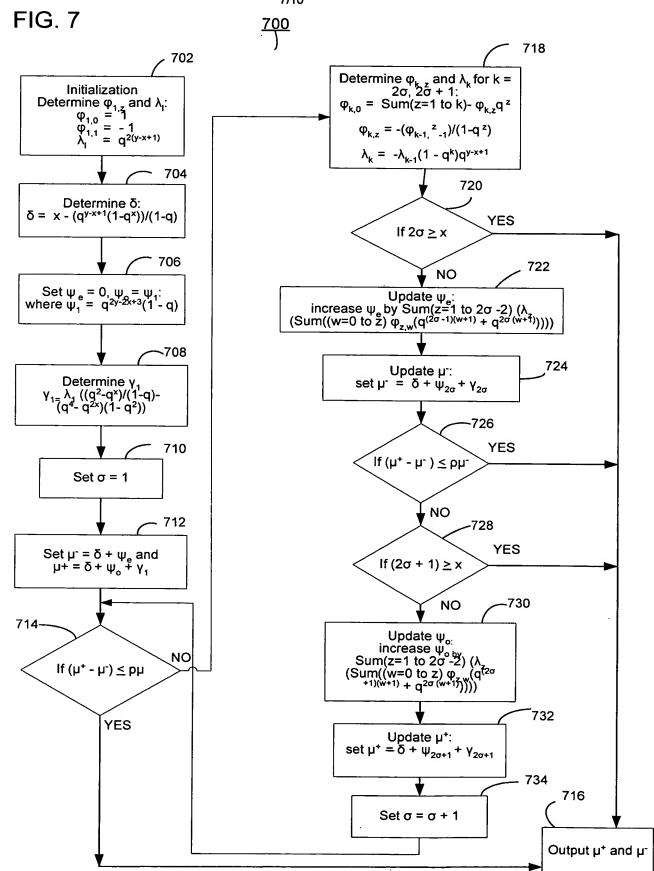
STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG ATTY REF.: 7784-000707

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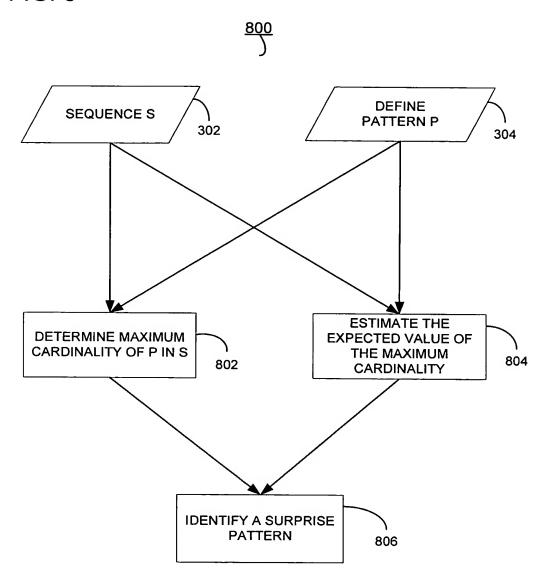
ATTY REF.: 7784-000707 MARK D. ELCHUK, HARNESS DICKEY & PIERCE, 248-641-1229



TITLE: SYSTEM/METHOD FOR ANALYZING A PATTERN IN A TIME-STAMPED EVENT SEQUENCE INVENTOR: CHANGZHOU WANG

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FIG. 8

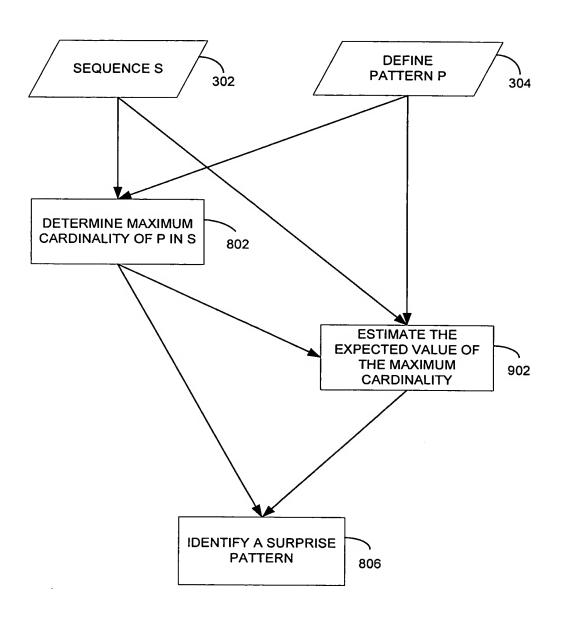


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FIG. 9





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